

# Yingdi Liu

## List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/2869578/publications.pdf>

Version: 2024-02-01

7  
papers

91  
citations

1937685  
4  
h-index

2272923  
4  
g-index

7  
all docs

7  
docs citations

7  
times ranked

34  
citing authors

#	ARTICLE	IF	CITATIONS
1	Embedded Deterministic Test Points. IEEE Transactions on Very Large Scale Integration (VLSI) Systems, 2017, 25, 2949-2961.	3.1	35
2	Deterministic Stellar BIST for In-System Automotive Test. , 2018, , .		19
3	Deterministic Stellar BIST for Automotive ICs. IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, 2020, 39, 1699-1710.	2.7	11
4	Staggered ATPG with capture-per-cycle observation test points. , 2018, , .		10
5	Time and Area Optimized Testing of Automotive ICs. IEEE Transactions on Very Large Scale Integration (VLSI) Systems, 2021, 29, 76-88.	3.1	10
6	X-Tolerant Compactor maXpress for In-System Test Applications With Observation Scan. IEEE Transactions on Very Large Scale Integration (VLSI) Systems, 2021, 29, 1553-1566.	3.1	4
7	X-Tolerant Tunable Compactor for In-System Test. , 2020, , .		2